
 **EEL 4744**
EEL 4744C: μ P Apps

Menu


- Debugging
 - > Why do we need to debug?
 - > When do we need to debug?
 - > How do we debug?
 - Before/as we code
 - After we code
 - > Common bugs



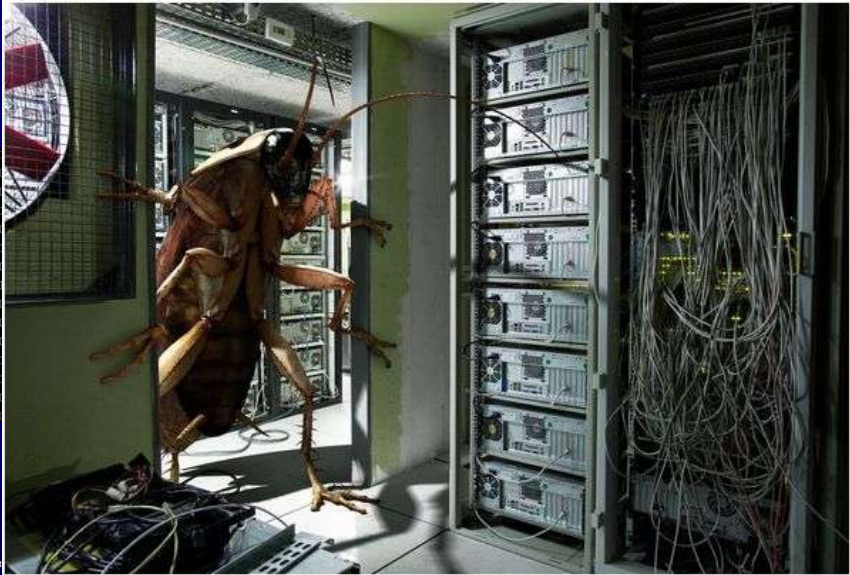
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Debugging




10101
10001
00101
00001
11000
00011
00100
11001
10011
11000
00101
0010
0010
0101
0101

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Software/Hardware Bug

- A **software bug** is an error or failure in a program
- Fixing bugs is called **debugging**
- Software bugs cost US economy
 - > In 2002, **\$59 billion** = \$ 59,000,000,000 [Source](#)
 - > In 2016, **\$1.1 trillion** = \$1,100,000,000,000 [Source](#)
 - > In 2020, **\$2.1 trillion!** [Source](#)
 - > Estimate for 2021, **\$6 trillion!** [Source](#)
- Grace Brewster Murray Hopper, in 1946 (at Harvard) had an early **electromechanical computer**
 - > It was not working
 - > She found a **bug** (a moth) inside
 - > She remove the bug, and it worked
 - She **debugged** the computer
 - > She gets credit for the **BUG** in hardware and software



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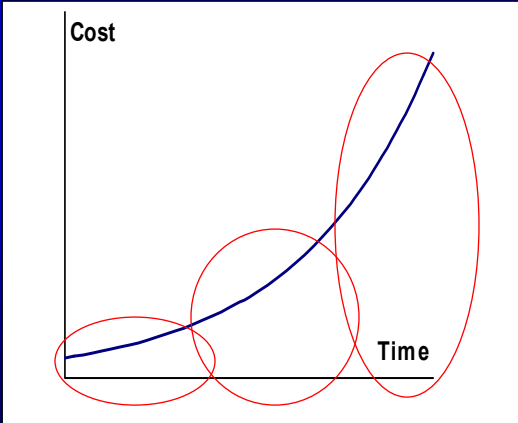
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The Cost of Debugging

- Increases exponentially in time



Example:

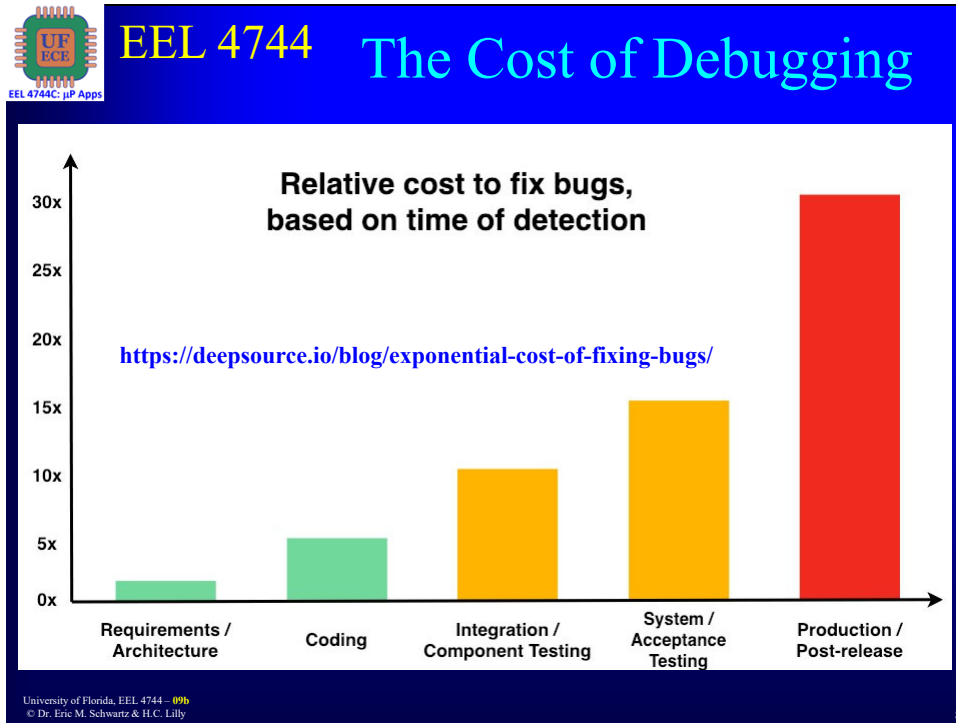
```
int i,j;
for (;i++;i<50)
```

Cost:

80 hrs * \$25/hr = \$2000
with overhead, \$4000

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When should we start debugging?

- Before we code/design (easiest)
- As we code/design
- After we code/design (hardest)

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How to debug before and as we code

- Make code modular
 - > Should be small, independent, self-contained
 - > Inter-modular bugs are the worst kind
- Well defined functions and parameters
- Start simple; work toward more complex
- Evaluate all degenerate cases
 - > Code defensively
- Run/debug each small module as we write it

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Which of the principles does this code violate?

```
.ORG 0x0000
    rjmp MAIN
.ORG 0x200
MAIN:
; Load stack pointer


    ldi  r16, 0x37
    :
ISR:
    add  r16, R17
    :
    RETI
```

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- Modularity
 - > ISR depends on the main routine to initialize r16
- Warning: Dangerous bug!**
- Well defined parameters
 - > Register r16 is probably not documented as a parameter to ISR
- Degenerate cases
 - > What if Main or some other previously executed subroutine ever changes r16?



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How to debug after we code (1)

- Be creative
- **Cardinal rule of debugging: Isolate the Error**
 - > Where does the problem occur?
- What do the hardware and software do?
- Stare at code
 - > Look at list file
- Memory dumps and stack traces

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How to debug after we code (2)

- Use breakpoints and single stepping
 - > Make sure memory and registers are as expected
- Write debug code
 - > Print
 - > Tags
 - > Outputs, LEDs
- **Keep it simple**

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Example of using tags

```
.ORG 0x0000
    rjmp MAIN
.ORG 0x200
MAIN:
; load stack ptr
    clr    r25
    :
    ldi   r25, 1
    :
    ldi   r25, 2
    :
    ldi   r25, 3
    :
```

- The goal is to locate an error
- Set up (and clear) a register e.g., r25, (or a variable in memory)
- Change the value in the register (or memory) at certain strategic locations
- You could use LEDs or print statements, if available

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Remember common error types

- Off by 1
- Zero case, -1 case, +1 case, MaxInt, MinInt
- No termination condition for a loop
- Variables not initialized
- Unexpected side effects
- Inter-modular bugs

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Example of Common Errors


```

.equ Size = 256
.org 0x2000
Table: .byte Size
...
MAIN:
    ldi XL, low(Table)
    ldi XH, high(Table)
    ldi r18, Size
Loop:
    dec r18
    ld r17, X+
    add r16, r17
    brne Done
    beq Loop
Done:
    :
```

- This program sums the contents of Table, in r16
- Can not put 256 into 8-bit register r18 (too big!)
- The first time through the loop, we add the contents of @Table+0 to r16 > r16 is **not** initialized to zero!
- DEC should be last thing before branches (since ADD could change flags)
- First branch should be BEQ or BRSH, not BRNE
- Degenerate case: r16 is probably too small to hold the sum of so many numbers

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Additional Comments

- Do something; divide and conquer
- Errors in ISRs are especially dangerous so take extra precautions
- Other assemblers may be available (for \$\$\$) that give better warning messages when things are “funny”
- When writing code (and designing hardware) keep in mind how you can test it
 - > Design in extra things that can help you test modules (hardware OR software)

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Debugging Hardware for EE/CpE

- Multimeter
- Logic (State) Analyzers = LSA = LA
- Oscilloscope = O-scope = Scope
- **All UF students own versions of these devices!**

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Multimeter

- Multimeter measures the following:
 - > Voltage and current (both AC and DC)
 - > Resistance
- The one on top cost less than \$4.00
 - > Used to get one in 3701; now it 3111
- The one on the bottom costs ~\$900.00
- These are used to measure a single signal at one time




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Logic (State) Analyzer

- Captures and displays multiple **digital** signals from a digital system as a function of time
- The time data can help us determine a design or program mistake
- LSA can use a **trigger** to look for specific combinations of signals (to see if they ever occur)
- Logic Analyzer can display from 1 to 256 signals, depending on the cost and complexity of the LSA
- For computer systems, they are often used to display **address bus**, **data bus**, and **control bus** values for hardware system debugging

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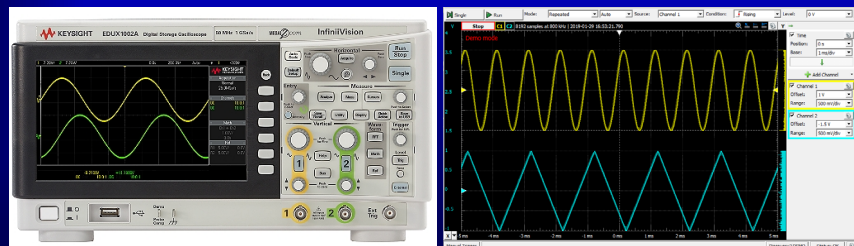
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Oscilloscope

- An oscilloscope displays the voltage of a signal as a function of time
- An o-scope is used for non-digital signals
- Most o-scopes have only one, two, or four channels
 - > I.e., the number of signals that you can see at the same time
 - > The scope to the left shows two signal channels
 - > The figure on the right is the **output** of a two channel scope
 - The top signal is a sinusoid waveform; the bottom is a triangle waveform



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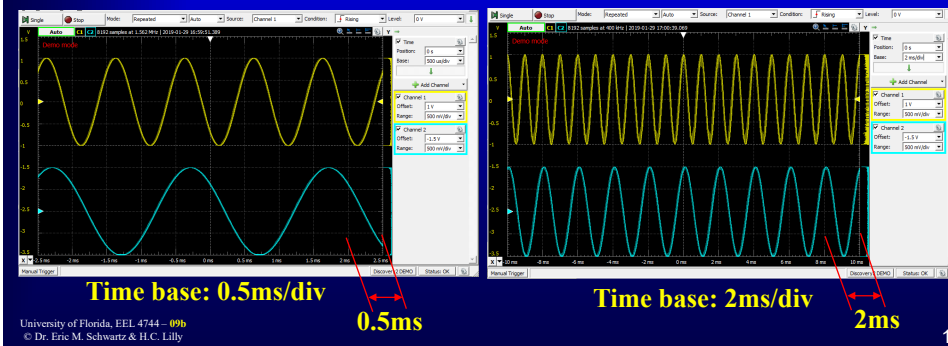
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Oscilloscope

- The **horizontal (time) scale** and vertical (voltage) scale can be changed
 - > The second scope output shows the time scale change by a factor of 4



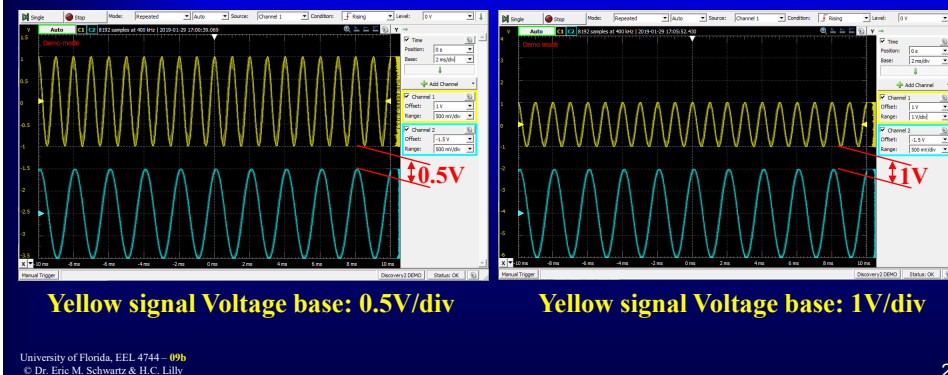
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Oscilloscope

- A similar scaling of the **vertical (voltage) scale** can be accomplished
 - > The below figure on the right show the top signal voltage changed by a factor of 4



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Digilent Analog Discovery (DAD)

- Your **DAD**, required in many ECE courses at UF (but less than a few years ago) and can be used as a replacement for all of these debugging tools!
 - > 2-Channel **O'scope** (5MHz bandwidth, 100Msample/sec)
 - > 16-Channel **Logic Analyzer** and Digital Pattern Generator
 - > 2-Channel **Waveform Generator**
 - > ±5VDC Power Supplies (+5V at 50mA, -5V at 50mA)
 - > **Spectrum Analyzer** (100Msample/sec)
 - > **Network Analyzer** (Bode, Nyquist, Nichols; 1Hz-10MHz)
 - > **Voltmeter** (AC, DC, ±25V), Digital I/O
 - > **Digital Bus Analyzers** (SPI, I2C, UART, Parallel)

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The End!

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